

PTO/SB/08A			Complete if Known		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			Application Number	10/597,374	
			Filing Date	07/21/2006	
			First Named Inventor	Chen Xu	
			Art Unit	2876	
			Examiner Name		
Sheet	1	of	2	Attorney Docket Number	CEDE 2132.8

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	1	2002/0185716	12/12/2002	Abys et al.	
	2	2002/0187364	12/12/2002	Heber et al.	
	3	2002/0192492	12/19/2002	Abys et al.	
	4	2003/0025182	02/06/2003	Abys et al.	
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	7	4,504,427	03/12/1985	Moyer	
	8	4,601,957	07/22/1986	Fujimoto et al.	
	9	4,749,626	06/07/1988	Kadija et al.	
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	18	6,248,455	06/19/2001	Adams et al.	
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	20	6,452,258	09/17/2002	Abys et al.	
	21	6,613,451	09/02/2003	Asahara et al.	
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	24	6,982,030	05/27/2004	Zhang et al.	

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Examiner Initials	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
	25	JP 59-222594	12/14/1984	Susumu et al.		
	26	DE 2129819	12/21/1972	Betschart		

Examiner Signature	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁶ Applicant is to place a check mark here if English Translation is attached or place an "A" here if English language abstract is attached.

SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Sheet	2	of	2	Attorney Docket Number	CEDE 2132.8

	27	DE 10159890	07/24/2003	Linde et al.	
OTHER ART – NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published			T ²
	28	BURSSE et al., "Tin Whiskers: Attributes and Mitigation", Carts Europe 2002: 16th Components Symposium, pgs 221-233			
	29	OSENBACH et al., "The Effects of Board Attachment Processing on Sn Whisker Formation on Electroplated Matte-Sn on Cu Alloy Lead Frames", IPC/JEDEC Conference, March 17, 2004			
	30	WIPO Preliminary Report on Patentability of PCT/US2005/001999 dated 08/03/2006, 6 pgs			
	31	XU et al., "Whisker Prevention", April 2003, pgs 1-8			
	32	XU et al., "Understanding Whisker Phenomenon - Driving Force for the Whisker Formation", Apex 2002, April 2002, pgs 1-6			
	33	XU et al., "Understanding Whisker Phenomenon: The Driving Force for Whisker Formation", www.circuitree.com , pgs 94-104, April 2002			
	34	VAN DER PAS et al., "Immersion Tin: The Final Answer for Lead-Free?", Printed Circuit Europe - 4th Quarter 2003, pgs 32-35			
	35	ZHANG et al., "Understanding Whisker Phenomenon Whisker Index and Tin/Copper, Tin/Nickel Interface", Apex 2002, pgs 1-11			
	36	ZHANG et al., "Tin Whisker Growth", Apex Expo, February 25, 2004			

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CEDE 2132.8

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of Chen Xu
Serial No. 10/597,374
Filed July 21, 2006
Confirmation No. 9982

Art Unit 2876

For PRESERVING SOLDERABILITY AND INHIBITING WHISKER GROWTH IN TIN
SURFACES OF ELECTRONIC COMPONENTS

October 26, 2006

TO THE COMMISSIONER FOR PATENTS,

SIR:

INFORMATION DISCLOSURE STATEMENT

* In accordance with 37 C.F.R. 1.97 and 1.98 and MPEP 609, and in compliance with the duty of disclosure set forth in 37 C.F.R. 1.56, applicants submit the attached PTO/SB/08A for consideration by the Patent and Trademark Office in the above-entitled application and to be made of record therein.

The references listed on the attached PTO/SB/08A have been previously submitted in parent application Serial No. 10/968,500 and, therefore, in accordance with MPEP 609, are not being provided at this time.

Respectfully submitted,



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